

ON Semiconductor®

# FCA20N60 N-Channel SuperFET MOSFET 600 V, 20 A, 190 m $\Omega$

#### **Features**

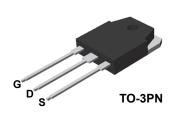
- 650V @ T<sub>1</sub> = 150°C
- Typ.  $R_{DS(on)}$  = 150 m $\Omega$
- Ultra Low Gate Charge (Typ.  $Q_g = 75 \text{ nC}$ )
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 165 pF )
- 100% Avalanche Tested

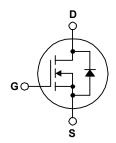
## **Applications**

- · Solar Inverter
- · AC-DC Power Supply

# **Description**

SuperFET® MOSFET is ON Semiconductor's first genera-tion of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.





## **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter			FCA20N60 / FCA20N60-F109	Unit
$V_{DSS}$	Drain to Source Voltage			600	V
$V_{GSS}$	Gate-Soure voltage			±30	V
I <sub>D</sub>	- Continuous ( $T_C = 25^{\circ}C$ )			20	^
	Drain Current	- Continuous (T <sub>C</sub> = 100°C)	- Continuous (T <sub>C</sub> = 100°C)		_ A
I <sub>DM</sub>	Drain Current	- Pulsed	- Pulsed (Note 1)		Α
E <sub>AS</sub>	Single Pulsed Avalanche	Energy	(Note 2)	690	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	20	Α
E <sub>AR</sub>	Repetitive Avalanche Ene	rgy	(Note 1)	20.8	mJ
dv/dt	Peak Diode Recovery dv/o	dt	(Note 3)	4.5	V/ns
Б		$(T_C = 25^{\circ}C)$		208	W
$P_{D}$	Power Dissipation	- Derate Above 25°C		1.67	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperate	ure for Soldering, 1/8" from Case for 5	Seconds	300	°C

### **Thermal Characteristics**

Symbol	Parameter	FCA20N60 / FCA20N60_F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	41.7	- 0/00

# **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCA20N60	FCA20N60	TO-3PN	Tube	N/A	N/A	30 units
FCA20N60-F109	FCA20N60	TO-3PN	Tube	N/A	N/A	30 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
D\/	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	600	-	-	V
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 150^{\circ} C$	-	650	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 20 A	-	700	-	V
_	Zoro Cata Valtaga Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	1	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	0.15	0.19	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A	-	17	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05.V.V 0.V	-	2370	3080	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz	-	1280	1665	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	-	95	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	65	85	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	-	165	-	pF
$Q_g$	Total Gate Charge at 10V	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 20 A,	-	75	98	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V	-	13.5	18	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	-	36	-	nC

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	62	135	ns
t <sub>r</sub>	Turn-On Rise Time	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 20 A,	-	140	290	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_G$ = 25 $\Omega$	-	230	470	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	65	140	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	20	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	60	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 20 A		-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{SD} = 20 \text{ A},$	-	530	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	10.5	-	μС

#### Notes:

- 1: Repetitive rating: pulse-width limited by maximum junction temperature.
- 2: I<sub>AS</sub> = 10 A, V<sub>DD</sub> = 50 V, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.
- 3: I  $_{SD}~\leq 20$  A, di/dt  $\leq 200$  A/µs, V  $_{DD} \leq BV _{DSS},$  starting T  $_{J}$  = 25°C.
- 4: Essentially independent of operating temperature typical characteristics.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

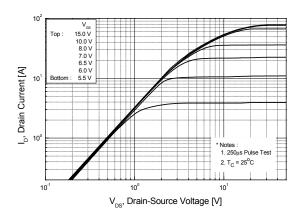


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

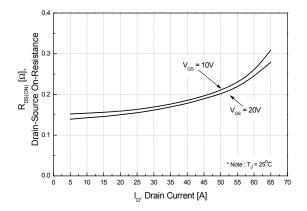
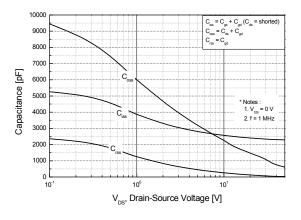


Figure 5. Capacitance Characteristics



**Figure 2. Transfer Characteristics** 

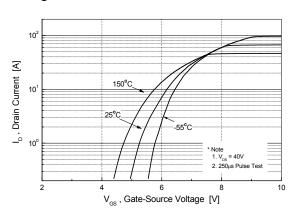


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

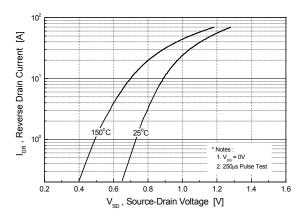
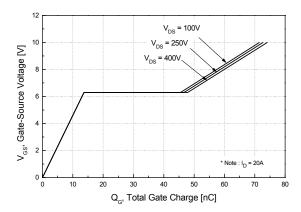


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

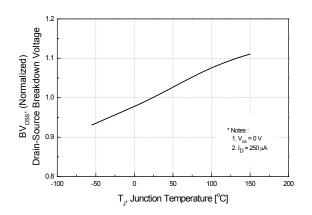


Figure 8. On-Resistance Variation vs. Temperature

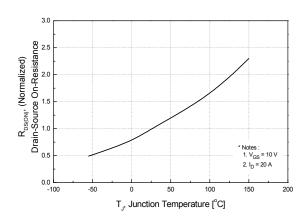


Figure 9. Maximum Safe Operating Area

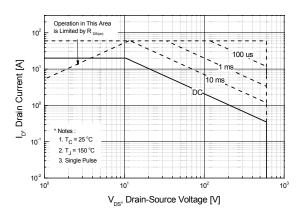


Figure 10. Maximum Drain Current vs. Case Temperature

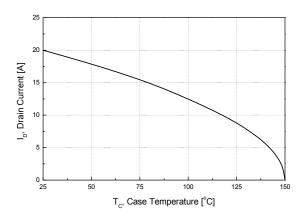
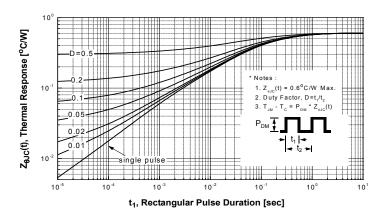


Figure 11. Transient Thermal Response Curve



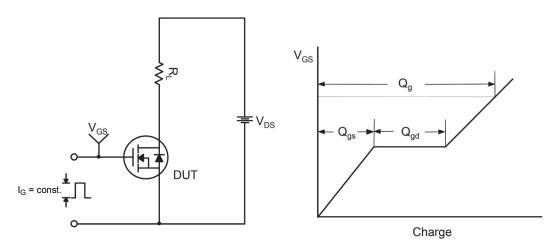


Figure 12. Gate Charge Test Circuit & Waveform

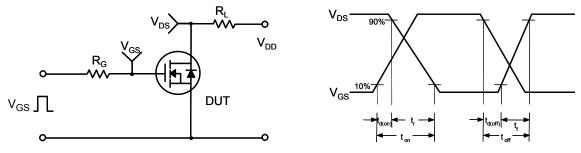


Figure 13. Resistive Switching Test Circuit & Waveforms

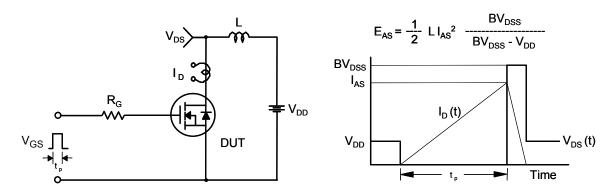
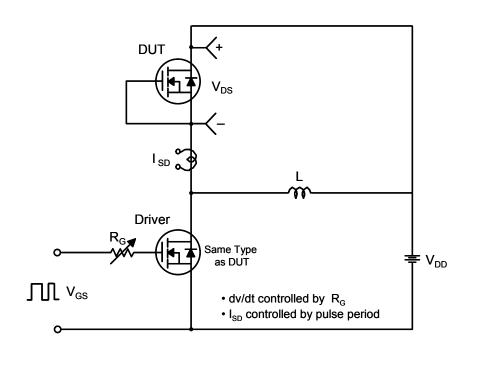


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



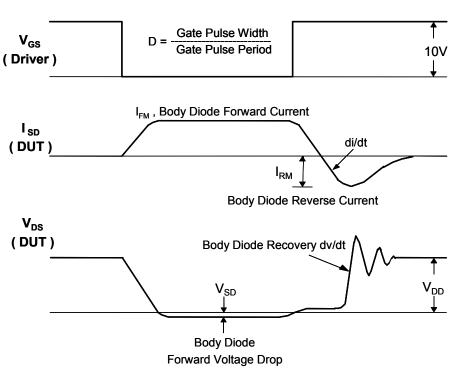


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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